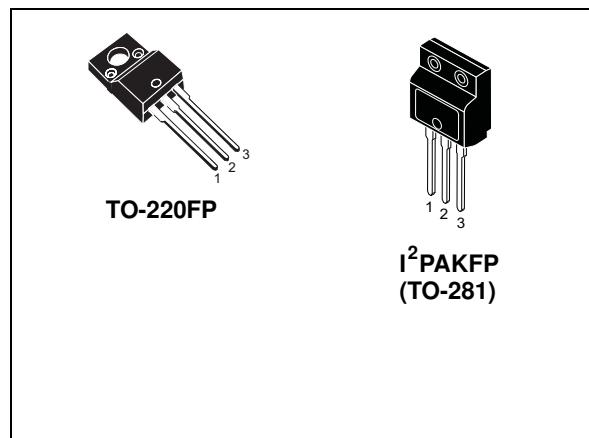
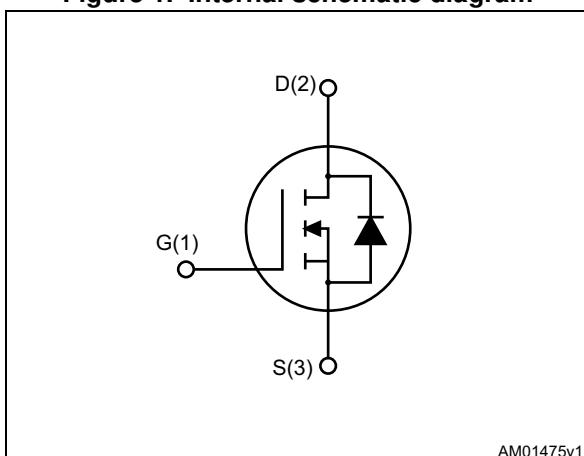


N-channel 650 V, 0.35 Ω typ., 12 A MDmesh™ II Power MOSFETs  
in TO-220FP and I<sup>2</sup>PAKFP packages

Datasheet - production data



**Figure 1. Internal schematic diagram**



## Features

Order code	V <sub>DSS</sub> @T <sub>jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STF15NM65N	710 V	0.38 Ω	12 A
STFI15NM65N			

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Applications

- Switching applications

## Description

These devices are N-channel Power MOSFETs developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFETs associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

Order code	Marking	Packages	Packing
STF15NM65N	15NM65N	TO-220FP	Tube
STFI15NM65N		I <sup>2</sup> PAKFP (TO-281)	

## Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value		Unit
		TO-220FP	I <sup>2</sup> PAKFP	
V <sub>DS</sub>	Drain source voltage	650		V
V <sub>GS</sub>	Gate source voltage	± 25		V
I <sub>D</sub>	Drain current continuous T <sub>c</sub> = 25 °C	12 <sup>(1)</sup>		A
I <sub>D</sub>	Drain current continuous T <sub>c</sub> = 100 °C	7.56		A
I <sub>DM</sub> <sup>(2)</sup>	Drain current pulsed	48		A
P <sub>TOT</sub>	Total dissipation at T <sub>c</sub> = 25 °C	30		W
dv/dt <sup>(3)</sup>	Peak diode recovery voltage slope	15		V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS from all three leads to external heatsink (t = 1 s; T <sub>C</sub> = 25 °C)	2500		V
T <sub>J</sub>	Operating junction temperature range	-55 to 150		°C
T <sub>stg</sub>	Storage temperature range			

1. Limited by maximum junction temperature.
2. Pulse width limited by safe operating area.
3. ISD ≤ 12 A, di/dt ≤ 400 A/μs, V<sub>Dpeak</sub> ≤ V<sub>(BR)DSS</sub>, V<sub>DD</sub> = 80 % V<sub>(BR)DSS</sub>

**Table 3. Thermal data**

Symbol	Parameters	Value		Unit
		TO-220FP	I <sup>2</sup> PAKFP	
R <sub>thjc</sub>	Thermal resistance junction-case	4.17		°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	62.5		°C/W

**Table 4. Avalanche characteristics**

Symbol	Parameters	Value	Unit
I <sub>AS</sub>	Avalanche current, repetitive or non-repetitive (pulse width limited by T <sub>jmax</sub> )	3	A
E <sub>AS</sub>	Single pulse avalanche energy (starting T <sub>J</sub> = 25 °C, I <sub>D</sub> = I <sub>AR</sub> , V <sub>DD</sub> = 50 V)	187	mJ

## 2 Electrical characteristics

( $T_{CASE} = 25^\circ\text{C}$  unless otherwise specified).

**Table 5. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0$ , $I_D = 1 \text{ mA}$	650			V
$I_{DSS}$	Zero gate voltage drain current	$V_{DD} = 650 \text{ V}$ , $V_{GS}=0$			1	$\mu\text{A}$
		$V_{DD} = 650 \text{ V}$ , $V_{GS} = 0$ $T_C = 125^\circ\text{C}^{(1)}$			100	$\mu\text{A}$
$I_{GSS}$	Gate body leakage	$V_{GS}= \pm 25 \text{ V}$ , $V_{DS} = 0 \text{ V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$I_D= 250 \mu\text{A}$ , $V_{GS} = V_{DS}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$I_D= 6 \text{ A}$ , $V_{GS}= 10\text{V}$		0.35	0.38	$\Omega$

1. Defined by design, not subject to production test

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Ma.	Unit
$C_{iss}$	Input capacitance	$V_{DS}= 50 \text{ V}$ , $f = 1\text{MHz}$ , $V_{GS}= 0 \text{ V}$	-	983	-	pF
$C_{oss}$	Output capacitance		-	57	-	pF
$C_{rss}$	Reverse capacitance		-	4.5	-	pF
$C_{osseq}^{(1)}$	Equivalent output. capacitance	$V_{DS} = 0 \text{ V}$ to $520 \text{ V}$ , $V_{GS} = 0 \text{ V}$	-	146	-	pF
$R_g$	Intrinsic gate resistance	$f = 1\text{MHz}$ $I_D = 0 \text{ A}$	-	4.6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD}= 520 \text{ V}$ , $I_D=12 \text{ A}$ , $V_{GS}= 10 \text{ V}$ (see <a href="#">Figure 13: Gate charge test circuit</a> )	-	33.3	-	nC
$Q_{gs}$	Gate source charge		-	5.7	-	nC
$Q_{gd}$	Gate-drain charge		-	17	-	nC

1. Cross eq: defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80 %  $V_{DSS}$ .

**Table 7. Switching times**

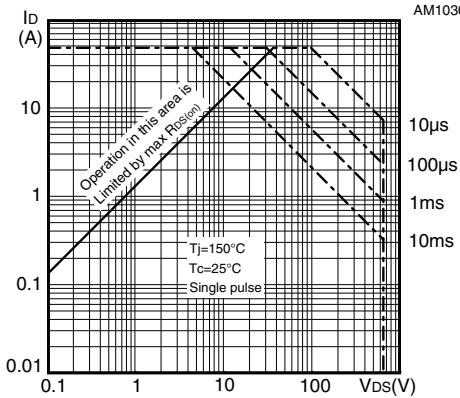
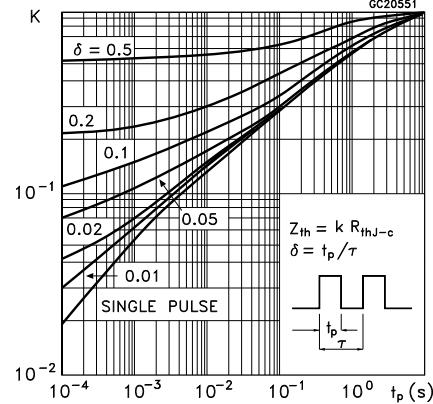
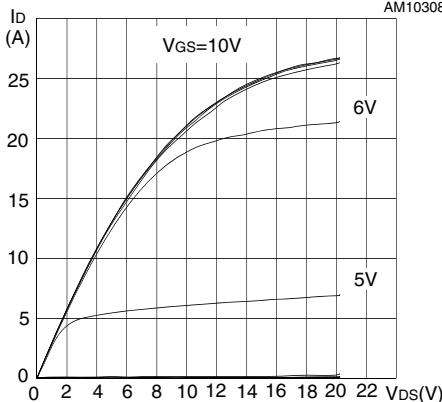
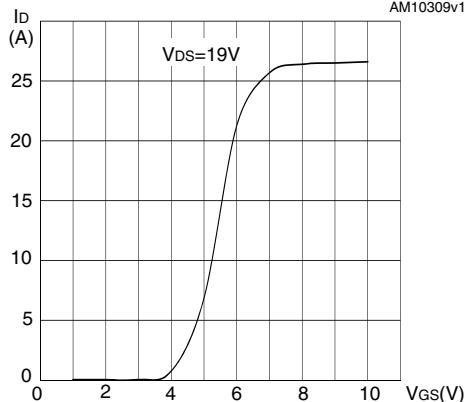
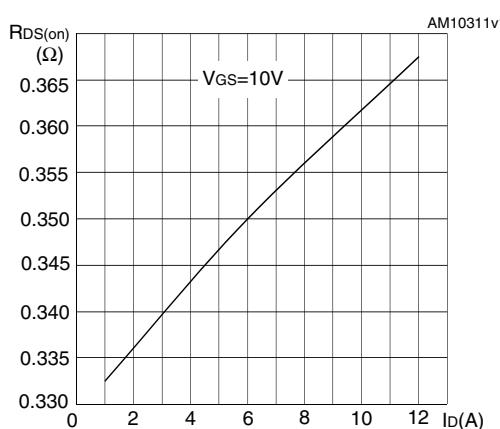
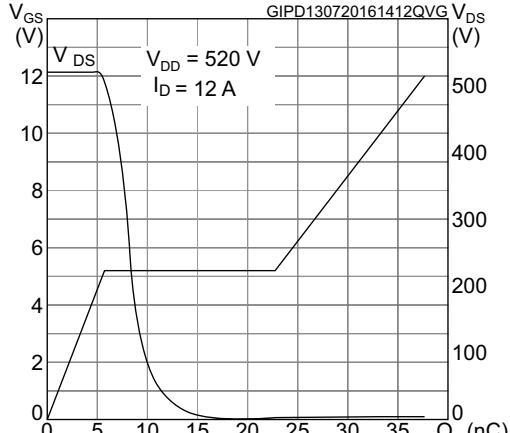
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD}= 325 \text{ V}$ , $I_D = 6 \text{ A}$ $R_g= 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 12: Switching times test circuit for resistive load</a> and <a href="#">Figure 17: Switching time waveform</a> )	-	55.5	-	ns
$t_r$	Rise time		-	8.5	-	ns
$t_{d(off)}$	Turn-off-delay time		-	14	-	ns
$t_f$	Fall time		-	11.4	-	ns

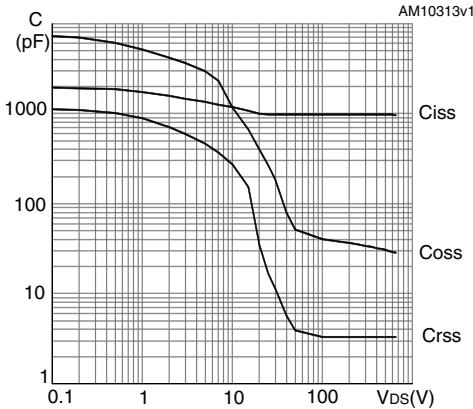
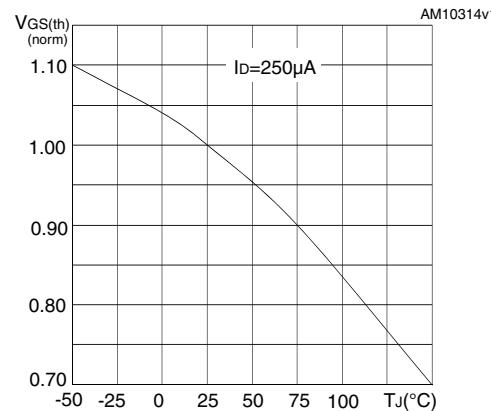
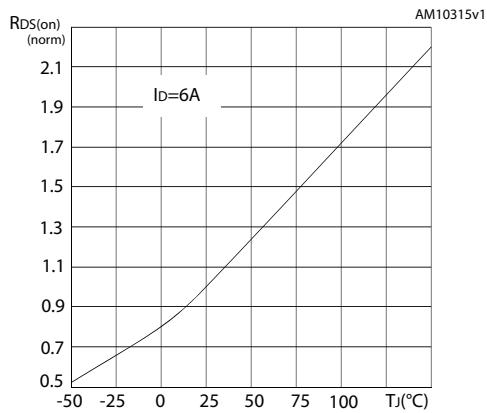
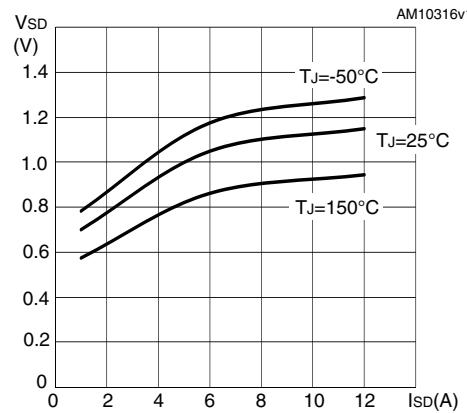
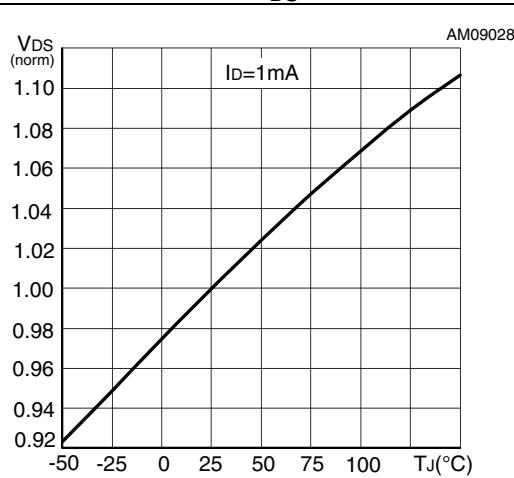
Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source drain current		-		12	A
$I_{SDM}^{(1)}$	Source drain current (pulsed)		-		48	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 12 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 12 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <i>Figure 14: Test circuit for inductive load switching and diode recovery times</i> )	-	428		ns
$Q_{rr}$	Reverse recovery charge		-	4.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	21.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 12 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}, T_j = 150^\circ\text{C}$ (see <i>Figure 14: Test circuit for inductive load switching and diode recovery times</i> )	-	570		ns
$Q_{rr}$	Reverse recovery charge		-	6.2		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	22		A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5 %

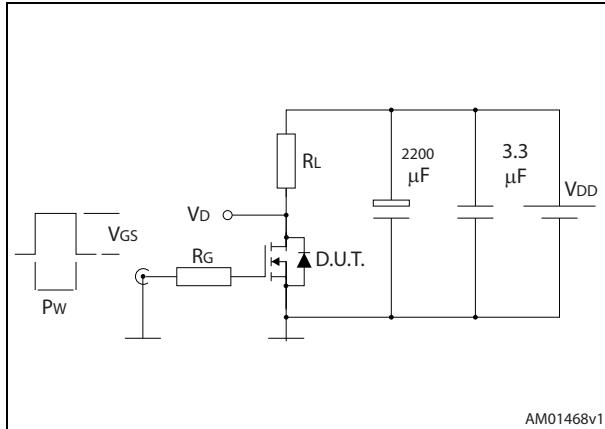
## 2.1 Electrical characteristics (curves)

**Figure 2. Safe operating area****Figure 3. Thermal impedance****Figure 4. Output characteristics****Figure 5. Transfer characteristics****Figure 6. Static drain-source on-resistance****Figure 7. Gate charge vs gate-source voltage**

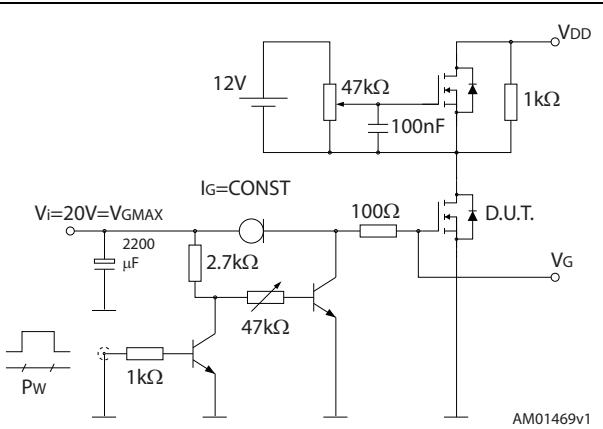
**Figure 8. Capacitance variations****Figure 9. Normalized gate threshold voltage vs temperature****Figure 10. Normalized on-resistance vs temp.****Source-drain diode forward characteristics****Figure 11. Normalized  $V_{DS}$  vs temperature**

### 3 Test circuits

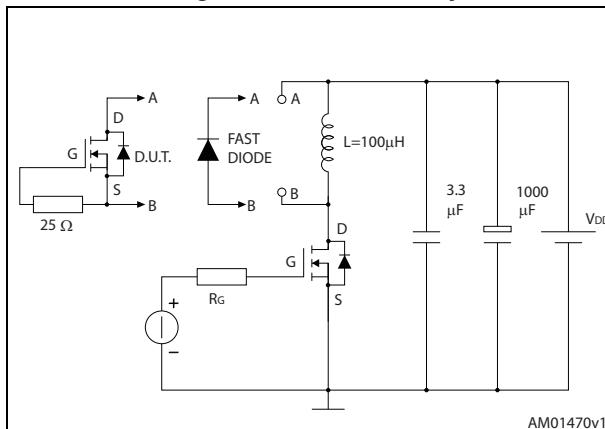
**Figure 12. Switching times test circuit for resistive load**



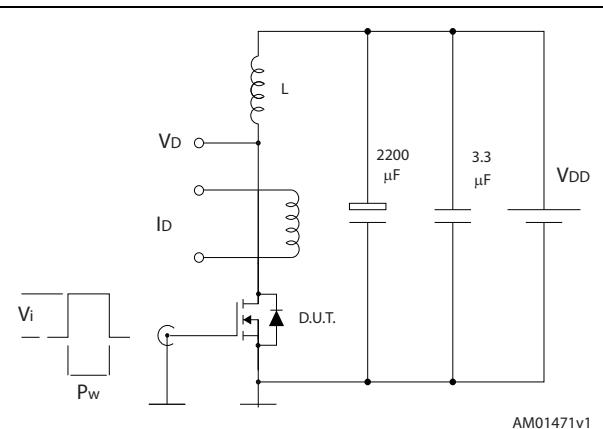
**Figure 13. Gate charge test circuit**



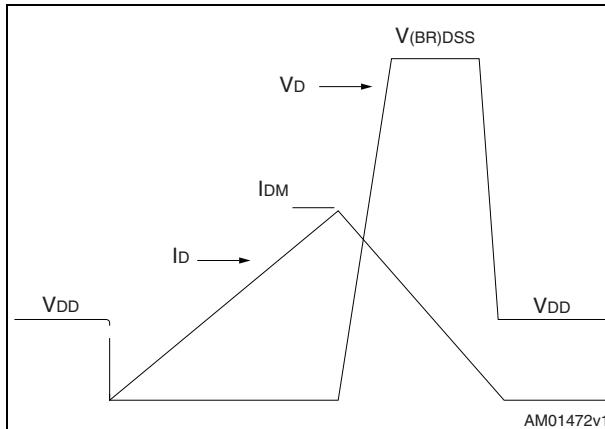
**Figure 14. Test circuit for inductive load switching and diode recovery times**



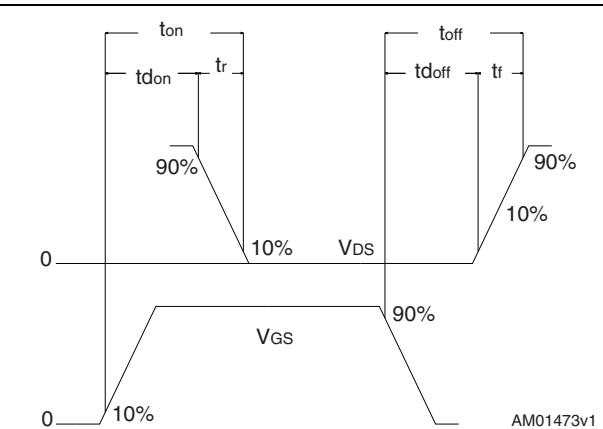
**Figure 15. Unclamped inductive load test circuit**



**Figure 16. Unclamped inductive waveform**



**Figure 17. Switching time waveform**

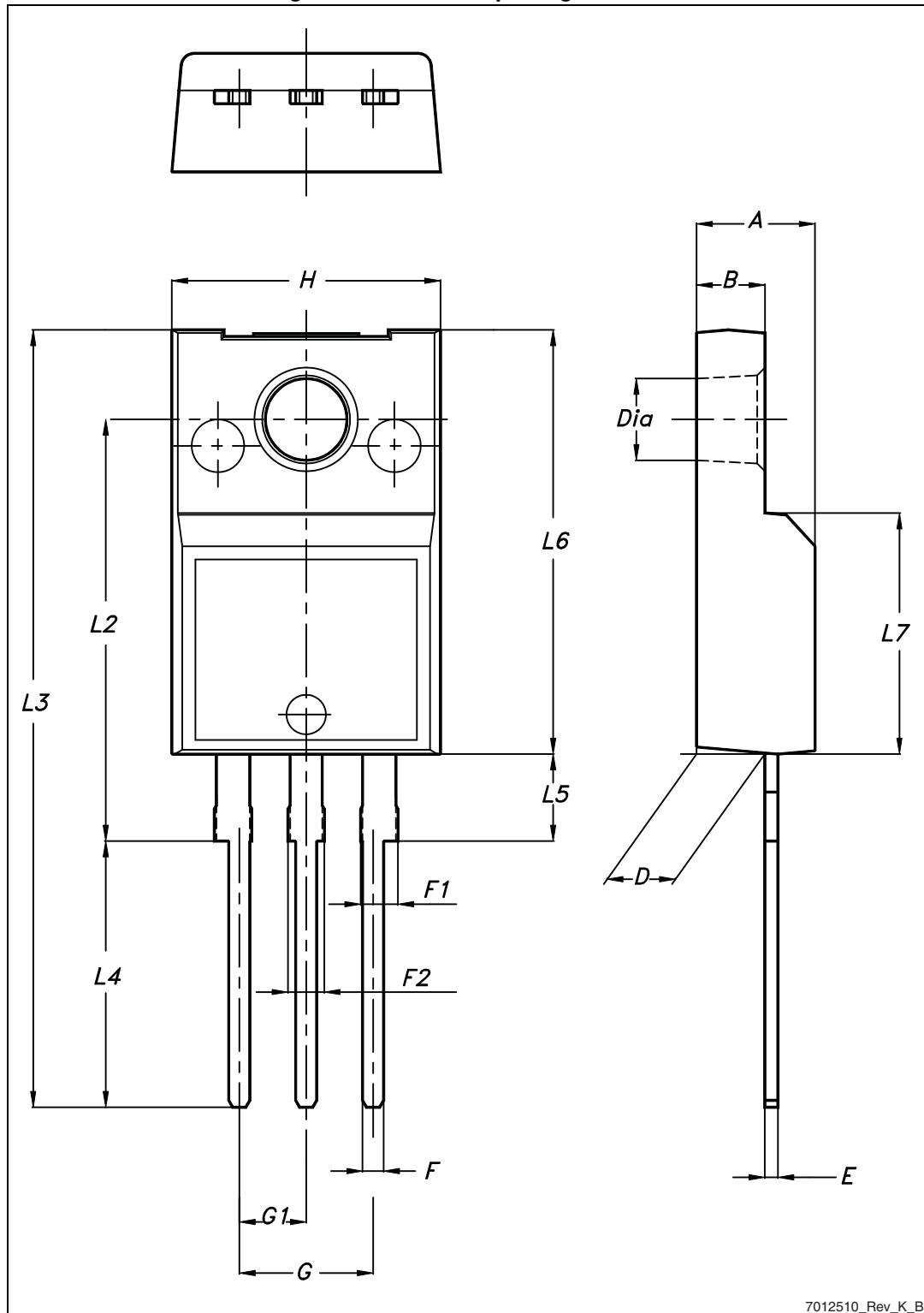


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 TO-220FP package information

Figure 18. TO-220FP package outline

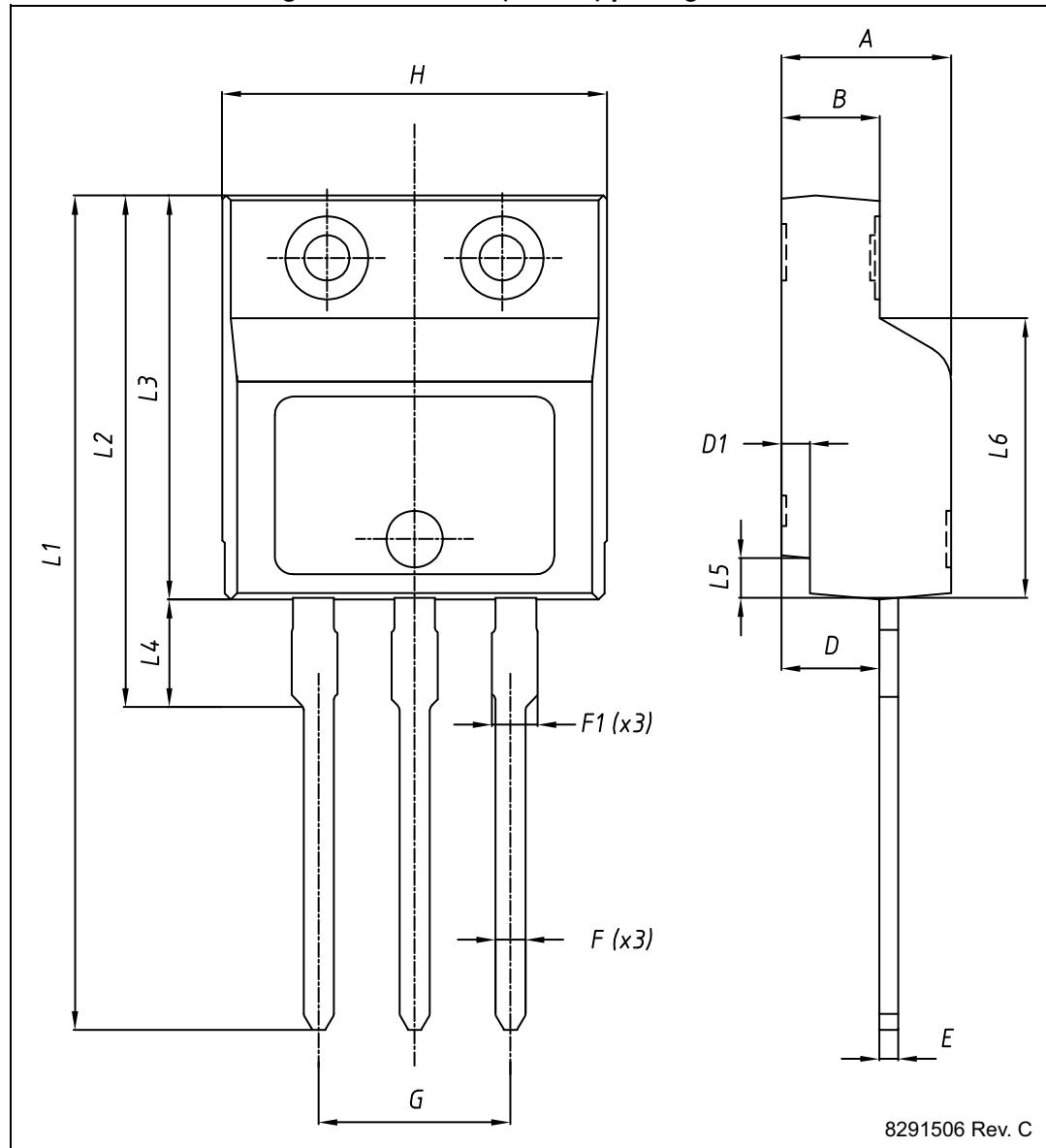


**Table 9. TO-220FP package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

## 4.2 I<sup>2</sup>PAKFP (TO-281) package information

Figure 19. I<sup>2</sup>PAKFP (TO-281) package outline



**Table 10. I<sup>2</sup>PAKFP (TO-281) package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95		5.20
H	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.50	7.60	7.70

## 5 Revision history

Table 11. Document revision history

Date	Revision	Changes
11-May-2011	1	Initial release.
21-Jun-2011	2	Document status promoted from preliminary data to datasheet, added Section 2.1: Electrical characteristics (curves).
17-Jul-2013	3	<ul style="list-style-type: none"><li>– Added: I<sup>2</sup>PAKFP package</li><li>– Added: <i>Table 10</i> and <i>Figure 22</i></li><li>– Updated: <i>Section 4: Package information</i></li><li>– Minor text changes.</li></ul>
25-Jul-2016	4	The part number STP15NM65N has been moved to a separate datasheet. Minor text changes.

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